	Application/Control No.	Applicant(s)/Patent Under Reexamination
Issue Classification	10772698	WU ET AL.
	Examiner	Art Unit
	Syed, Farhan M	2165

		Syed, Farnan M	C017	0	
	ORIGINAL	IAL	INTERN	INTERNATIONAL CLASSIFICATION	
CL	CLASS	SUBCLASS	CLAIMED	NON-CI	NON-CLAIMED
707		100	G 0 6 F	17 / 30	
	CROSS REFERENCE(S)	RENCE(S)			
CLASS	SUBCLASS (ON	SUBCLASS (ONE SUBCLASS PER BLOCK)			
707 2	3	200 202			
704 244					
,					
Farhan Syed	10/5/2007			Total Clain	Total Claims Allowed:
(Assistant Examiner)	(Date)				14
7	TO 8 1 01	Jeffrey Gaffin	1005/2007	O.G. Print Claim(s)	O.G. Print Figure
(Legal Instruments Examiner)		(Primary Examiner)	JERFREY CHAPFIN	1	-
U.S. Patent and Trademark Office	Office	18 / /	JPERVISORY PATENT EXAMINED		Part of Paper No.
				•	

SUPERVISORY PATENT EXAMINES TECHNOLOGY CENTER 2100